High Speed 8-Bit TL A/D Converter

FEATURES
100 MSPS ENCODE Rate
Very Low Input Capacitance-16 pF
Low Power-1 W
TTL Compatible Outputs
MIL-STD-883 Compliant Versions Available

## APPLICATIONS

Radar Guidance
Digital Oscilloscopes/ATE Equipment
Laser/Radar Warning Receivers
Digital Radio
Electronic Warfare (ECM, ECCM, ESM)
Communication/Signal Intelligence

## GENERAL DESCRIPTION

The AD9012 is an 8-bit, ultrahigh speed, analog-to-digital converter. The AD9012 is fabricated in an advanced bipolar process that allows operation at sampling rates up to 100 megasamples/second. Functionally, the AD9012 is comprised of 256 parallel comparator stages whose outputs are decoded to drive the TTL compatible output latches.
The exceptionally wide large-signal analog input bandwidth of 160 MHz is due to an innovative comparator design and very close attention to device layout considerations. The wide input bandwidth of the AD9012 allows very accurate acquisition of high speed pulse inputs without an external track-and-hold. The comparator output decoding scheme minimizes false codes, which is critical to high speed linearity.
The AD9012 is available in two grades: one with 0.5 LSB linearity and one with 0.75 LSB linearity. Both versions are

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FUNCTIONAL BLOCK DIAGRAM

offered in an industrial grade, $-25^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$, packaged in a $28-l e a d$ DIP and a 28 -lead JLCC. The military temperature range devices, $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$, are available in ceramic DIP and LCC packages and are compliant to MIL-STD-883 Class B.
The AD9012 is available in versions compliant with MIL-STD-883. Refer to the Analog Devices Military Products Databook or current AD9012/883B data sheet for detailed specifications.

| Parameter | Temp | Test Level | AD9012AQ/AJ |  |  | AD9012BQ/BJ |  |  | AD9012SQ/SE |  |  | AD9012TQ/TE |  |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | Min | Typ | Max | Min | Typ | Max | Min | Typ | Max | Min | Typ | Max |  |
| RESOLUTION |  |  | 8 |  |  | 8 |  |  | 8 |  |  | 8 |  |  | Bits |
| DC ACCURACY <br> Differential Linearity <br> Integral Linearity <br> No Missing Codes | $\begin{aligned} & 25^{\circ} \mathrm{C} \\ & \mathrm{Full} \\ & 25^{\circ} \mathrm{C} \\ & \text { Full } \\ & \text { Full } \end{aligned}$ | $\begin{aligned} & \text { I } \\ & \text { VI } \\ & \text { I } \\ & \text { VI } \\ & \text { VI } \end{aligned}$ | Guar | $\begin{gathered} 0.6 \\ 0.6 \\ \text { anteed } \end{gathered}$ | $\begin{aligned} & 0.75 \\ & 1.0 \\ & 1.0 \\ & 1.2 \end{aligned}$ | Guar | 0.4 <br> 0.4 <br> teed | $\begin{aligned} & 0.5 \\ & 0.75 \\ & 0.5 \\ & 1.2 \end{aligned}$ | Guar | $\begin{array}{r} 0.6 \\ 0.6 \\ \text { ateed } \end{array}$ | $\begin{aligned} & 0.75 \\ & 1.0 \\ & 1.0 \\ & 1.2 \end{aligned}$ | Guar | 0.4 <br> 0.4 <br> nteed | $\begin{aligned} & 0.5 \\ & 0.75 \\ & 0.5 \\ & 1.2 \end{aligned}$ | $\begin{aligned} & \text { LSB } \\ & \text { LSB } \\ & \text { LSB } \\ & \text { LSB } \end{aligned}$ |
| INITIAL OFFSET ERROR <br> Top of Reference Ladder <br> Bottom of Reference Ladder <br> Offset Drift Coefficient | $\begin{aligned} & 25^{\circ} \mathrm{C} \\ & \text { Full } \\ & 25^{\circ} \mathrm{C} \\ & \text { Full } \\ & \text { Full } \end{aligned}$ | $\begin{aligned} & \text { I } \\ & \text { VI } \\ & \text { I } \\ & \text { VI } \\ & \text { V } \end{aligned}$ |  | 7 <br> 6 <br> 25 | $\begin{aligned} & 15 \\ & 18 \\ & 10 \\ & 13 \end{aligned}$ |  |  | $\begin{aligned} & 15 \\ & 18 \\ & 10 \\ & 13 \end{aligned}$ |  |  | $\begin{aligned} & 15 \\ & 18 \\ & 10 \\ & 13 \end{aligned}$ |  |  | $\begin{aligned} & 15 \\ & 18 \\ & 10 \\ & 13 \end{aligned}$ | mV <br> mV <br> mV <br> mV <br> $\mu \mathrm{V} /{ }^{\circ} \mathrm{C}$ |
| ANALOG INPUT <br> Input Bias Current ${ }^{1}$ <br> Input Resistance <br> Input Capacitance <br> Large Signal Bandwidth ${ }^{2}$ <br> Analog Input Slew Rate ${ }^{3}$ | $\begin{aligned} & 25^{\circ} \mathrm{C} \\ & \text { Full } \\ & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \end{aligned}$ | $\begin{aligned} & \text { I } \\ & \text { VI } \\ & \text { I } \\ & \text { III } \\ & \text { V } \end{aligned}$ | 25 | $\begin{aligned} & 60 \\ & 200 \\ & 16 \\ & 160 \\ & 440 \end{aligned}$ | $\begin{aligned} & 200 \\ & 200 \\ & \\ & 18 \end{aligned}$ | 25 | $\begin{aligned} & 60 \\ & \\ & 200 \\ & 16 \\ & 160 \\ & 440 \end{aligned}$ | $\begin{aligned} & 200 \\ & 200 \\ & 18 \end{aligned}$ | 25 | $\begin{aligned} & 60 \\ & 200 \\ & 16 \\ & 160 \\ & 440 \end{aligned}$ | $\begin{aligned} & 200 \\ & 200 \\ & \\ & 18 \end{aligned}$ | 25 | $\begin{aligned} & 60 \\ & \\ & 200 \\ & 16 \\ & 160 \\ & 440 \end{aligned}$ | $\begin{aligned} & 200 \\ & 200 \\ & 18 \end{aligned}$ | $\mu \mathrm{A}$ <br> $\mu \mathrm{A}$ <br> $\mathrm{k} \Omega$ <br> pF <br> MHz <br> V/ $\mu \mathrm{s}$ |
| REFERENCE INPUT <br> Reference Ladder Resistance Ladder Temperature Coefficient Reference Input Bandwidth | $\begin{aligned} & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \end{aligned}$ | $\begin{aligned} & \text { VI } \\ & \text { V } \\ & \text { V } \end{aligned}$ | 40 | $\begin{aligned} & 80 \\ & 0.25 \\ & 10 \end{aligned}$ | 110 | 40 | $\begin{aligned} & 80 \\ & 0.25 \\ & 10 \end{aligned}$ | 110 | 40 | $\begin{aligned} & 80 \\ & 0.25 \\ & 10 \end{aligned}$ | 110 | 40 | $\begin{aligned} & 80 \\ & 0.25 \\ & 10 \end{aligned}$ | 110 | $\begin{aligned} & \Omega \\ & \Omega /{ }^{\circ} \mathrm{C} \\ & \mathrm{MHz} \end{aligned}$ |
| DYNAMIC PERFORMANCE <br> Conversion Rate Aperture Delay Aperture Uncertainty (Jitter) Output Delay ( $\left.\mathrm{t}_{\mathrm{PD}}\right)^{4,5}$ Transient Response ${ }^{6}$ Overvoltage Recovery Time ${ }^{7}$ Output Rise Time ${ }^{4}$ Output Fall Time ${ }^{4}$ Output Time Skew ${ }^{4,8}$ | $\begin{aligned} & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \end{aligned}$ | $\begin{aligned} & \mathrm{I} \\ & \mathrm{~V} \\ & \mathrm{~V} \\ & \mathrm{I} \\ & \mathrm{~V} \\ & \mathrm{~V} \\ & \mathrm{I} \\ & \mathrm{I} \\ & \mathrm{~V} \end{aligned}$ | 75 4 | $\begin{aligned} & 100 \\ & 3.8 \\ & 15 \\ & 4.9 \\ & 8 \\ & 8 \\ & 6.6 \\ & 3.3 \\ & 3.0 \end{aligned}$ | $11$ $8.0$ $4.3$ | 75 4 | $\begin{aligned} & 100 \\ & 3.8 \\ & 15 \\ & 4.9 \\ & 8 \\ & 8 \\ & 6.6 \\ & 3.3 \\ & 3.0 \end{aligned}$ | 11 <br> 8.0 <br> 4.3 | $75$ <br> 4 | $\begin{aligned} & 100 \\ & 3.8 \\ & 15 \\ & 4.9 \\ & 8 \\ & 8 \\ & 6.6 \\ & 3.3 \\ & 3.0 \end{aligned}$ | 11 <br> 8.0 <br> 4.3 | $75$ <br> 4 | $\begin{aligned} & 100 \\ & 3.8 \\ & 15 \\ & 4.9 \\ & 8 \\ & 8 \\ & 6.6 \\ & 3.3 \\ & 3.0 \end{aligned}$ | 11 <br> 8.0 <br> 4.3 | MSPS <br> ns <br> ps <br> ns <br> ns <br> ns <br> ns <br> ns <br> ns |
| ENCODE INPUT <br> Logic " 1 " Voltage ${ }^{4}$ <br> Logic "0" Voltage ${ }^{4}$ <br> Logic "1" Current <br> Logic "0" Current <br> Input Capacitance ENCODE Pulsewidth (Low) ${ }^{9}$ ENCODE Pulsewidth (High) ${ }^{9}$ | Full <br> Full <br> Full <br> Full <br> $25^{\circ} \mathrm{C}$ <br> $25^{\circ} \mathrm{C}$ <br> $25^{\circ} \mathrm{C}$ | VI <br> VI <br> VI <br> VI <br> V <br> I <br> I | 2.0   <br>   0.8 <br>   400 <br>  2.5  <br> 2.5   <br> 2.5   |  |  | 2.0   <br>   0.8 <br>   250 <br>  200  <br> 2.5   <br> 2.5   |  |  | 2.0   <br>   0.8 <br>   250 <br>  2.5  <br> 2.5   <br> 2.5   |  |  | 2.0   <br>   0.8 <br>   250 <br>  2.5  <br>  200  <br> 2.5   <br> 2.5   |  |  | V <br> V <br> $\mu \mathrm{A}$ <br> $\mu \mathrm{A}$ <br> pF <br> ns <br> ns |
| OVERFLOW INHIBIT INPUT <br> 0 V Input Current | Full | VI |  | 200 | 250 |  | 200 | 250 |  | 200 | 250 |  | 200 | 250 | $\mu \mathrm{A}$ |
| AC LINEARITY ${ }^{10}$ <br> Effective Bits ${ }^{11}$ <br> In-Band Harmonics <br> DC to 1.23 MHz <br> DC to 9.3 MHz <br> DC to 19.3 MHz <br> Signal-to-Noise Ratio ${ }^{12}$ <br> Noise Power Ratio ${ }^{13}$ | $\begin{aligned} & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \end{aligned}$ | V <br> I <br> V <br> V <br> I <br> V | 48 46 | $\begin{aligned} & 7.5 \\ & \\ & 55 \\ & 50 \\ & 44 \\ & 47.6 \\ & 37 \end{aligned}$ |  | $48$ $46$ | $\begin{aligned} & 7.5 \\ & \\ & 55 \\ & 50 \\ & 44 \\ & 47.6 \\ & 37 \end{aligned}$ |  | 48 46 | $\begin{aligned} & 7.5 \\ & 55 \\ & 50 \\ & 44 \\ & 47.6 \\ & 37 \end{aligned}$ |  | 48 46 | $7.5$ <br> 55 <br> 50 <br> 44 <br> 47.6 <br> 37 |  | Bits <br> dBc <br> dBc <br> dBc <br> dBc <br> dBc |
| DIGITAL OUTPUT <br> Logic " 1 " Voltage <br> Logic "0" Voltage | Full Full | $\begin{aligned} & \text { VI } \\ & \text { VI } \end{aligned}$ | 2.4 |  | 0.4 | 2.4 |  | 0.4 | 2.4 |  | 0.4 | 2.4 |  | 0.4 | $\begin{aligned} & \text { V } \\ & \mathrm{V} \end{aligned}$ |
| POWER SUPPLY ${ }^{14}$ <br> Positive Supply Current (+5.0 V) <br> Supply Current (-5.2 V) <br> Nominal Power Dissipation Reference Ladder Dissipation Power Supply Rejection Ratio ${ }^{15}$ | $\begin{aligned} & 25^{\circ} \mathrm{C} \\ & \text { Full } \\ & 25^{\circ} \mathrm{C} \\ & \text { Full } \\ & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \end{aligned}$ | $\begin{aligned} & \text { I } \\ & \text { VI } \\ & \text { I } \\ & \text { VI } \\ & \text { V } \\ & \text { V } \end{aligned}$ |  | 33 <br> 152 <br> 955 <br> 44 <br> 0.85 | $\begin{aligned} & 45 \\ & 48 \\ & 179 \\ & 191 \\ & \\ & 2.5 \end{aligned}$ |  | 33 <br> 152 <br> 955 <br> 44 <br> 0.85 | 45 <br> 48 <br> 179 <br> 191 $2.5$ |  | $33$ <br> 152 $955$ $44$ $0.8$ | $\begin{aligned} & 45 \\ & 48 \\ & 179 \\ & 191 \\ & \\ & 2.5 \end{aligned}$ |  | 33 <br> 152 $955$ <br> 44 <br> 0.8 | 45 <br> 48 <br> 179 <br> 191 <br> 2.5 | mA <br> mA <br> mA <br> mA <br> mW <br> mW <br> $\mathrm{mV} / \mathrm{V}$ |

## NOTES

${ }^{1}$ Measured with analog input $=0 \mathrm{~V}$.
${ }^{2}$ Measured by FFT analysis where fundamental is -3 dBc .
${ }^{3}$ Input slew rate derived from rise time ( $10 \%$ to $90 \%$ ) of full-scale step input.
${ }^{4}$ Outputs terminated with two equivalent 'LS00 type loads. (See load circuit.)
${ }^{5}$ Measured from ENCODE into data out for LSB only.
${ }^{6}$ For full-scale step input, 8 -bit accuracy is attained in specified time
${ }^{7}$ Recovers to 8 -bit accuracy in specified time, after $150 \%$ full-scale input overvoltage.
${ }^{8}$ Output time skew includes high-to-low and low-to-high transitions as well as bit-to-bit time skew differences.
${ }^{9}$ ENCODE signal rise/fall times should be less than 30 ns for normal operation.
${ }^{10}$ Measured at 75 MSPS ENCODE rate. Harmonic data based on worst-case harmonics.
${ }^{11}$ Analog input frequency $=1.23 \mathrm{MHz}$.
${ }^{12}$ RMS signal to rms noise, including harmonics with 1.23 MHz . Analog input signal.
${ }^{13} \mathrm{NPR}$ measured @ 0.5 MHz . Noise source is $250 \mathrm{~mW}(\mathrm{rms})$ from 0.5 MHz to 8 MHz .
${ }^{14}$ Supplies should remain stable within $\pm 5 \%$ for normal operation.
${ }^{15}$ Measured at $-5.2 \mathrm{~V} \pm 5 \%$ and $+5.0 \mathrm{~V} \pm 5 \%$.
Specifications subject to change without notice.

## ABSOLUTE MAXIMUM RATINGS ${ }^{1}$

Positive Supply Voltage (+ $\mathrm{V}_{\mathrm{S}}$ ) . . . . . . . . . . . . . . . . . . . . . 6 V
Analog to Digital Supply Voltage Differential (-V) ... 0.5 V
Negative Supply Voltage ( $-\mathrm{V}_{\mathrm{S}}$ ) . . . . . . . . . . . . . . . . . . . . -6 V
Analog Input Voltage . . . . . . . . . . . . . . . . . . . . . $-\mathrm{V}_{\mathrm{S}}$ to +0.5 V
ENCODE Input Voltage . . . . . . . . . . . . . . . . . -0.5 V to +5 V
OVERFLOW INH Input Voltage . . . . . . . . . . . -5.2 V to 0 V
Reference Input Voltage $\left(+\mathrm{V}_{\mathrm{REF}},-\mathrm{V}_{\mathrm{REF}}\right)^{2} \ldots-3.5 \mathrm{~V}$ to +0.1 V
Differential Reference Voltage . . . . . . . . . . . . . . . . . . . 2.1 V
Reference Midpoint Current . . . . . . . . . . . . . . . . . . . $\pm 4 \mathrm{~mA}$
Digital Output Current . . . . . . . . . . . . . . . . . . . . . . . 30 mA
Operating Temperature Range
AD9012AQ/BQ/AJ/BJ . . . . . . . . . . . . . . . $-25^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$
AD9012SE/SQ/TE/TQ . . . . . . . . . . . . . . $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$
Storage Temperature Range . . . . . . . . . . . . $-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$
Junction Temperature ${ }^{3}$. . . . . . . . . . . . . . . . . . . . . . . . $150^{\circ} \mathrm{C}$
Lead Soldering Temperature ( 10 sec ) . . . . . . . . . . . . $300^{\circ} \mathrm{C}$
NOTES
${ }^{1}$ Absolute Maximum Ratings are limiting values, to be applied individually, and beyond which the serviceability of the circuit may be impaired. Functional operability under any of these conditions is not necessarily implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.
${ }^{2}+V_{\text {REF }} \geq-V_{\text {REF }}$ under all circumstances.
${ }^{3}$ Maximum junction temperature ( $\mathrm{T}_{\mathrm{J}}$ max) should not exceed $150^{\circ} \mathrm{C}$ for ceramic and plastic packages:
$\mathrm{T}_{\mathrm{J}}=\mathrm{PD}\left(\theta_{\mathrm{JA}}\right)+\mathrm{T}_{\mathrm{A}}$
$\mathrm{PD}\left(\theta_{\mathrm{J}}\right)+\mathrm{Tc}$
where:
PD = power dissipation
$\theta_{\mathrm{JA}}=$ thermal impedance from junction to ambient ( ${ }^{\circ} \mathrm{C} / \mathrm{W}$ )
$\theta_{\mathrm{JC}}=$ thermal impedance from junction to case $\left({ }^{\circ} \mathrm{C} / \mathrm{W}\right)$
$\mathrm{T}_{\mathrm{A}}=$ ambient temperature ( ${ }^{\circ} \mathrm{C}$ )
$\mathrm{T}_{\mathrm{C}}=$ case temperature ( ${ }^{\circ} \mathrm{C}$ )
Typical thermal impedances are:
Ceramic DIP $\theta_{\mathrm{JA}}=42^{\circ} \mathrm{C} / \mathrm{W} ; \theta_{\mathrm{JC}}=10^{\circ} \mathrm{C} / \mathrm{W}$
Ceramic LCC $\theta_{\mathrm{JA}}=50^{\circ} \mathrm{C} / \mathrm{W} ; \theta_{\mathrm{JC}}=15^{\circ} \mathrm{C} / \mathrm{W}$
JLCC $\theta_{\mathrm{JA}}=59^{\circ} \mathrm{C} / \mathrm{W} ; \theta_{\mathrm{JC}}=15^{\circ} \mathrm{C} / \mathrm{W}$
Recommended Operating Conditions

| Parameter | Input Voltage (V) |  |  |
| :--- | :--- | :---: | :--- |
|  | Min | Nominal | Max |
| $-\mathrm{V}_{\mathrm{S}}$ | -5.46 | -5.20 | -4.94 |
| $+\mathrm{V}_{\mathrm{S}}$ | +4.75 | +5.00 | +5.25 |
| $+\mathrm{V}_{\mathrm{REF}}$ | $-\mathrm{V}_{\mathrm{REF}}$ | 0.0 | +0.1 |
| $-\mathrm{V}_{\mathrm{REF}}$ | -2.1 | -2.0 | $+\mathrm{V}_{\mathrm{REF}}$ |
| Analog Input | $-\mathrm{V}_{\mathrm{REF}}$ |  | $+\mathrm{V}_{\mathrm{REF}}$ |



Figure 1. Load Circuit

## EXPLANATION OF TEST LEVELS

## Test Level

I - $100 \%$ production tested.
II - $100 \%$ production tested at $25^{\circ} \mathrm{C}$, and sample tested at specified temperatures. AC testing done on sample basis.
III - Sample tested only.
IV - Parameter is guaranteed by design and characterization testing.
V - Parameter is a typical value only.
VI - All devices are $100 \%$ production tested at $25^{\circ} \mathrm{C} .100 \%$ production tested at temperature extremes for extended temperature devices; guaranteed by design and characterization testing for industrial devices.

## ORDERING GUIDE

| Device | Linearity | Temperature <br> Ranges | Package <br> Options* |
| :--- | :--- | :--- | :--- |
| AD9012AQ | 0.75 LSB | $-25^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | $\mathrm{Q}-28$ |
| AD9012BQ | 0.50 LSB | $-25^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | $\mathrm{Q}-28$ |
| AD9012AJ | 0.75 LSB | $-25^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | $\mathrm{J}-28 \mathrm{~A}$ |
| AD9012BJ | 0.50 LSB | $-25^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | $\mathrm{J}-28 \mathrm{~A}$ |
| AD9012SQ | 0.75 LSB | $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ | $\mathrm{Q}-28$ |
| AD9012SE | 0.75 LSB | $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ | $\mathrm{E}-28 \mathrm{~A}$ |
| AD9012TQ | 0.50 LSB | $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ | $\mathrm{Q}-28$ |
| AD9012TE | 0.50 LSB | $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ | $\mathrm{E}-28 \mathrm{~A}$ |

*E = Leadless Ceramic Chip Carrier; J = Ceramic Leaded Chip Carrier; $\mathrm{Q}=$ Cerdip .

## CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although the AD9012 features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.

PIN FUNCTION DESCRIPTIONS


PIN CONFIGURATIONS



Figure 2. Timing Diagram


Figure 3. Input Output Circuits

DIE LAYOUT AND MECHANICAL INFORMATION


Die Dimensions . . . . 111 mils $\times 123$ mils $\times 15$ mils $( \pm 2)$ mils Pad Dimensions . . . . . . . . . . . . . . . . . . . . . . . 4 mils $\times 4$ mils Metallization ............................................ . . Gold
Backing . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . None
Substrate Potential . . . . . . . . . . . . . . . . . . . . . . . . . . . . . $-V_{S}$
Passivation . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . Nitride
Die Attach . . . . . . . . . . . . . . . . . . . Gold Eutectic (Ceramic)
. . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . Epoxy (Plastic)
Bond Wire . . . . . . . 1 mil to 1.3 mil Gold; Gold Ball Bonding


ALL RESISTORS $\pm 5 \%$
ALL CAPACITORS $\pm \mathbf{2 0 \%}$
ALL SUPPLY VOLTAGES $\pm 5 \%$
OPTION \#1 (STATIC) AD1 $=-2.0 \mathrm{~V} ;$ AD2 $=+2.4 \mathrm{~V}$ OPTION \#2 (DYNAMIC) SEE WAVEFORMS


Figure 4. Burn-In Diagram

## APPLICATION INFORMATION

The AD9012 is compatible with all standard TTL logic families. However, to operate at the highest ENCODE rates, the supporting logic around the AD9012 will need to be equally fast. Two possible choices are the AS and the ALS families. Whichever of the TTL logic families is used, special care must be exercised to keep digital switching noise away from the analog circuits around the AD9012. The two most critical items are the digital supply lines and the digital ground return.
The input capacitance of the AD9012 is an exceptionally low 16 pF . This allows the use of a wide range of input amplifiers, both hybrid and monolithic. To take full advantage of the 160 MHz input bandwidth of the AD9012, a hybrid amplifier such as the AD 9610 will be required. For those applications that do not require the full input bandwidth of the AD 9012 , some of the more traditional monolithic amplifiers, such as the AD846, should work very well. Overall performance with monolithic amplifiers can be improved by inserting a $40 \Omega$ resistor in series with the amplifier output.
The output data is buffered through the TTL compatible output latches. In addition to the latch propagation delay ( $\mathrm{t}_{\mathrm{pD}}$ ), all data is delayed by one clock cycle before becoming available at the outputs. Both the analog-to-digital conversion cycle and the data transfer to the output latches are triggered on the rising edge of the TTL compatible ENCODE signal (see Figure 2).
The AD9012 also incorporates a HYSTERESIS control pin that provides from 0 mV to 10 mV of additional hysteresis in the comparator input stages. Adjustments in the HYSTERESIS control voltage may help to improve noise immunity and overall performance in harsh environments.
The OVERFLOW INH pin of the AD9012 determines how the converter handles overrange inputs (AIN $\geq+\mathrm{V}_{\text {REF }}$ ). In the "enabled" state (floating at -5.2 V ), the OVERFLOW INH output will be at logic HIGH and all other outputs will be at logic LOW for overrange inputs (return-to-zero operation). In the "inhibited" state (tied to ground), the OVERFLOW INH output will be at logic LOW for overrange inputs, and all other digital outputs will be at logic HIGH (nonreturn-to-zero operation).
The AD9012 provides outstanding error rate performance. This is due to tight control of comparator offset matching and a fault tolerant decoding stage. Additional improvements in error rate are possible through the addition of hysteresis (see HYSTERESIS control pin). This level of performance is extremely important in fault sensitive applications, such as digital radio (QAM).
Dramatic improvements in comparator design and construction give the AD9012 excellent dynamic characteristics, namely SNR (signal-to-noise ratio). The 160 MHz input bandwidth and low error rate performance give the AD9012 an SNR of 47 dB with a 1.23 MHz input. High SNR performance is particularly important in broadcast video applications where signals may pass through the converter several times before the processing is complete. Pulse signature analysis, commonly performed in advanced radar receivers, is another area that is especially dependent on high quality dynamic performance.

## LAYOUT SUGGESTIONS

Designs using the AD9012, such as all high speed devices, must follow a few basic layout rules to ensure optimum performance. Essentially, these guidelines are meant to avoid many of the problems associated with high speed designs. The first requirement is for a substantial ground plane around and under the AD9012. Separate ground plane areas for the digital and analog components may be useful, but the separate grounds should be connected together at the AD9012 to avoid the effects of "ground loop" currents.
The second area that requires an extra degree of attention involves the three reference inputs, $+\mathrm{V}_{\mathrm{REF}}, \mathrm{REF}_{\mathrm{MID}}$, and $-\mathrm{V}_{\mathrm{REF}}$. The $+\mathrm{V}_{\text {REF }}$ input and the $-\mathrm{V}_{\text {REF }}$ input should both be driven from a low impedance source (note that the $+\mathrm{V}_{\text {REF }}$ input is typically tied to analog ground). A low drift amplifier should provide satisfactory results, even over an extended temperature range. Adjustments at the $\mathrm{REF}_{\text {MID }}$ input may be useful in improving the integral linearity by correcting any reference ladder skews.
The reference inputs should be adequately decoupled to ground through $0.1 \mu \mathrm{~F}$ chip capacitors to limit the effects of system noise on conversion accuracy. The power supply pins must also be decoupled to ground to improve noise immunity; $0.1 \mu \mathrm{~F}$ and $0.01 \mu \mathrm{~F}$ chip capacitors should be very effective.

The analog input signal is brought into the AD9012 through two separate input pins. It is very important that the two input pins be driven symmetrically with equal length electrical connections. Otherwise, aperture delay errors may degrade converter performance at high frequencies.


Figure 5. Typical Application


Figure 6. Evaluation Circuit


Figure 7. Dynamic Performance

## OUTLINE DIMENSIONS

28-Terminal Ceramic Leadless Chip Carrier [LCC]
(E-28A)
Dimensions shown in inches and (millimeters)


CONTROLLING DIMENSIONS ARE IN INCHES; MILLIMETER DIMENSIONS (IN PARENTHESES) ARE ROUNDED-OFF INCH EQUIVALENTS FOR REFERENCE ONLY AND ARE NOT APPROPRIATE FOR USE IN DESIGN

## 28-Lead Ceramic Leaded Chip Carrier - J-Formed Lead [JLCC] (J-28A)

Dimensions shown in inches and (millimeters)


CONTROLLING DIMENSIONS ARE IN INCHES; MILLIMETERS DIMENSIONS (IN PARENTHESES) ARE ROUNDED-OFF INCH EQUIVALENTS FOR REFERENCE ONLY AND ARE NOT APPROPRIATE FOR USE IN DESIGN

## 28-Lead Ceramic Dual In-Line Package [CERDIP]

(Q-28)
Dimensions shown in inches and (millimeters)


Revision History

